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<u>L2</u>	debug\$5 near15 (host\$3 or master) and (break or break near1 point\$1) near15 reset\$6	38	<u>L2</u>
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0-	Access the IEEE Enterprise File Cabinet	Conference on , 18-20 Sep 1989 Pages:21 - 25 [Abstract] [PDF Full-Text (432 KB)] IEE CNF
A Pi	rint Format	Setting break-points in distributed time-triggered architecture Smaili, I.; Ademaj, A.; High-Level Design Validation and Test Workshop, 2002. Seventh IEEE International, 27-29 Oct. 2002 Pages: 57 - 62 [Abstract] [PDF Full-Text (672 KB)] IEEE CNF

4 Breaking an application specific instruction-set processor: the first towards embedded software testing

Dielissen, J.T.M.H.; Otero Mathijssen, B.L.; Huisken, J.A.; High-Level Design Validation and Test Workshop, 2002. Seventh IEEE International, 27-29 Oct. 2002 Pages:89 - 92

[Abstract] [PDF Full-Text (372 KB)] **IEEE CNF**

5 A dynamic debugger for asynchronous distributed algorithms

Sorel, P.E.; Fernandez, M.G.; Ghosh, S.;

Software, IEEE, Volume: 11, Issue: 1, Jan. 1994

Pages:69 - 76

[Abstract] [PDF Full-Text (964 KB)] **IEEE JNL**

6 Detecting nondeterminacy in parallel programs

Emrath, P.A.; Ghosh, S.; Padua, D.A.;

Software, IEEE, Volume: 9, Issue: 1, Jan. 1992

Pages:69 - 77

[Abstract] [PDF Full-Text (1376 KB)] **IEEE JNL**

7 Fully IEEE1149.1 compatible DFT solution for MIPS CPU CORE

Zhengyi Lu; Chengshou Sun;

ASIC, 2003. Proceedings. 5th International Conference on , Volume: 2 , 21-2

2003

Pages:1140 - 1144 Vol.2

[Abstract] [PDF Full-Text (367 KB)] IEEE CNF

8 Debug facilities in the TriMedia CPU64 architecture

Vranken, H.;

Test Workshop 1999. Proceedings. European , 25-28 May 1999

Pages: 76 - 81

[Abstract] [PDF Full-Text (96 KB)] **IEEE CNF**

9 Compiler optimization and its impact on development of real-time systems

Tucker, K.; Solomon, E.; Littlejohn, K.;

Digital Avionics Systems Conference, 1998. Proceedings., 17th DASC. The

AIAA/IEEE/SAE, Volume: 1, 31 Oct.-7 Nov. 1998

Pages:C12/1 - C12/6 vol.1

[Abstract] [PDF Full-Text (472 KB)] **IEEE CNF**

10 High-level CHILL debugging system in cross-development environ:

YoungJoon Byun; Young-Sik Chung; Byung Sun Lee;

Parallel and Distributed Processing, 1998. PDP '98. Proceedings of the Sixth

Euromicro Workshop on , 21-23 Jan. 1998

Pages:211 - 216

[PDF Full-Text (884 KB)] [Abstract] **IEEE CNF**

11 A caching compiler for C

Koehler, B.; Horspool, R.N.;

Communications, Computers, and Signal Processing, 1995. Proceedings. IEEE

е

Pacific Rim Conference on , 17-19 May 1995

Pages:141 - 144

[Abstract] [PDF Full-Text (356 KB)] IEEE CNF

12 A proposed real-time ADA test

Newport, J.R.;

Aerospace and Electronics Conference, 1994. NAECON 1994., Proceedings of IEEE 1994 National , 23-27 May 1994

Pages:932 - 936 vol.2

[Abstract] [PDF Full-Text (256 KB)] IEEE CNF

13 Software abort and multiprocessor debugging

Baek Youngsik; Jin Sungil;

TENCON '93. Proceedings. Computer, Communication, Control and Power Engineering.1993 IEEE Region 10 Conference on , Issue: 0 , 19-21 Oct. 1993 Pages: 237 - 241 vol.1

[Abstract] [PDF Full-Text (300 KB)] IEEE CNF

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